# imall

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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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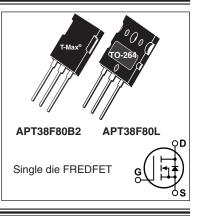


### APT38F80B2 APT38F80L

800V, 41A, 0.24 $\Omega$  Max, t<sub>rr</sub>  $\leq$ 300ns

## **N-Channel FREDFET**

Power MOS 8<sup>TM</sup> is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t<sub>rr</sub>, soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C<sub>rss</sub>/C<sub>iss</sub> result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



#### **FEATURES**

- Fast switching with low EMI
- Low t<sub>rr</sub> for high reliability
- Ultra low C<sub>rss</sub> for improved noise immunity
- Low gate charge
- Avalanche energy rated
- RoHS compliant 🥖

#### TYPICAL APPLICATIONS

- ZVS phase shifted and other full bridge
- Half bridge
- PFC and other boost converter
- Buck converter
- Single and two switch forward
- Flyback

#### **Absolute Maximum Ratings**

Symbol	Parameter	Ratings	Unit
I <sub>D</sub>	Continuous Drain Current @ T <sub>C</sub> = 25°C	41	
	Continuous Drain Current @ T <sub>C</sub> = 100°C	26	A
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	150	
V <sub>GS</sub>	Gate-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy	1710	mJ
I <sub>AR</sub>	Avalanche Current, Repetitive or Non-Repetitive	20	А

#### **Thermal and Mechanical Characteristics**

Symbol	Characteristic	Min	Тур	Max	Unit	
P <sub>D</sub>	Total Power Dissipation @ $T_{C} = 25^{\circ}C$			1040	W	
$R_{_{ ext{ heta}JC}}$	Junction to Case Thermal Resistance			0.12	0.12 °C/W	
$R_{_{ hetaCS}}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11			
T_,T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55		150	- °C	
Τ <sub>L</sub>	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W <sub>T</sub>	Deckore Weight		0.22		oz	
	Package Weight		6.2		g	
Torque	Mounting Targue (TO 264 Deckage), 4,40 er M2 eerow			10	in∙lbf	
	Mounting Torque (TO-264 Package), 4-40 or M3 screw			1.1	N∙m	

**Static Characteristics** 

#### T<sub>J</sub> = 25°C unless otherwise specified

APT38F80B2 L

Symbol	Parameter	Test Conditions		Min	Тур	Max	Unit
V <sub>BR(DSS)</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250 \mu A$		800			V
$\Delta V_{BR(DSS)} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, $I_D = 250\mu A$			0.87		V/°C
R <sub>DS(on)</sub>	Drain-Source On Resistance <sup>3</sup>	$V_{GS} = 10V, I_D = 20A$			0.19	0.24	Ω
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 2.5 \text{mA}$		2.5	4	5	V
$\Delta V_{GS(th)} / \Delta T_J$	Threshold Voltage Temperature Coefficient				-10		mV/°C
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 800V	$T_J = 25^{\circ}C$			250	μA
DSS		$V_{GS} = 0V$	$T_J = 125^{\circ}C$			1000	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS} = \pm 30V$				±100	nA

#### **Dynamic Characteristics**

#### T<sub>J</sub> = 25°C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
9 <sub>fs</sub>	Forward Transconductance	$V_{DS} = 50V, I_{D} = 20A$		38		S
C <sub>iss</sub>	Input Capacitance			8070		
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		140		
C <sub>oss</sub>	Output Capacitance			805		
C <sub>o(cr)</sub> ④	Effective Output Capacitance, Charge Related			380		pF
C <sub>o(er)</sub> (5)	Effective Output Capacitance, Energy Related	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 533V$		190		
Q <sub>g</sub>	Total Gate Charge			260		nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 0$ to 10V, $I_D = 20A$ , $V_{DS} = 400V$		44		
Q <sub>gd</sub>	Gate-Drain Charge	V <sub>DS</sub> = 400V		135		
t <sub>d(on)</sub>	Turn-On Delay Time	Resistive Switching		46		
t <sub>r</sub>	Current Rise Time	V <sub>DD</sub> = 533V, I <sub>D</sub> = 20A		65		ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{G} = 2.2\Omega^{\textcircled{0}}, V_{GG} = 15V$		200		115
t <sub>f</sub>	Current Fall Time			60		<u> </u>

#### **Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
۱ <sub>s</sub>	Continuous Source Current (Body Diode)	MOSFET symbol showing the			41	А
I <sub>SM</sub>	Pulsed Source Current (Body Diode) <sup>①</sup>	integral reverse p-n junction diode (body diode)			150	
V <sub>SD</sub>	Diode Forward Voltage	$I_{SD} = 20A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.2	V
t <sub>rr</sub>	Reverse Recovery Time	T <sub>J</sub> = 25°C		250	300	20
rr		T <sub>J</sub> = 125°C		485	600	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_{SD} = 20A^{(3)}$ $T_J = 25^{\circ}C$		2		
~rr		$V_{DD} = 100V$ $T_{J} = 125^{\circ}C$		6.7		- μC
l <sub>rrm</sub>	Reverse Recovery Current	$di_{SD}/dt = 100A/\mu s$ $T_J = 25^{\circ}C$		13		۸
		T <sub>J</sub> = 125°C		22		A
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 20A$ , di/dt $\le 1000A/\mu$ s, $V_{DD} = 533V$ , $T_{J} = 125^{\circ}C$			20	V/ns

(1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

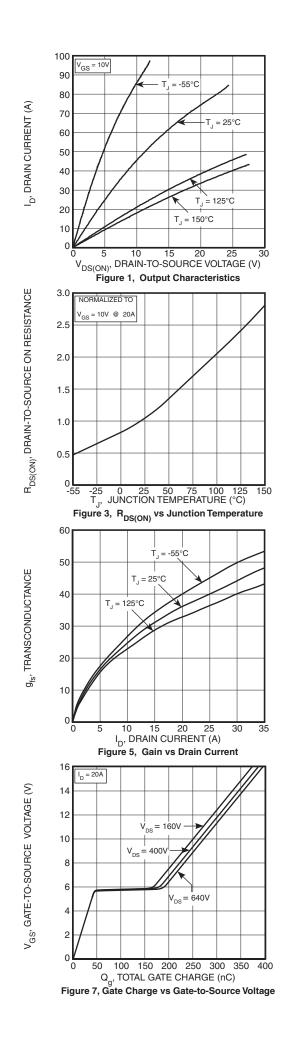
(2) Starting at  $T_J = 25^{\circ}$ C, L = 8.55mH,  $R_G = 25\Omega$ ,  $I_{AS} = 20$ A.

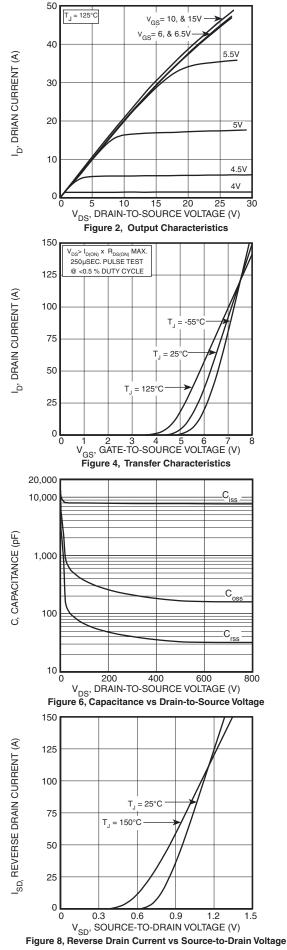
(3) Pulse test: Pulse Width <  $380\mu$ s, duty cycle < 2%.

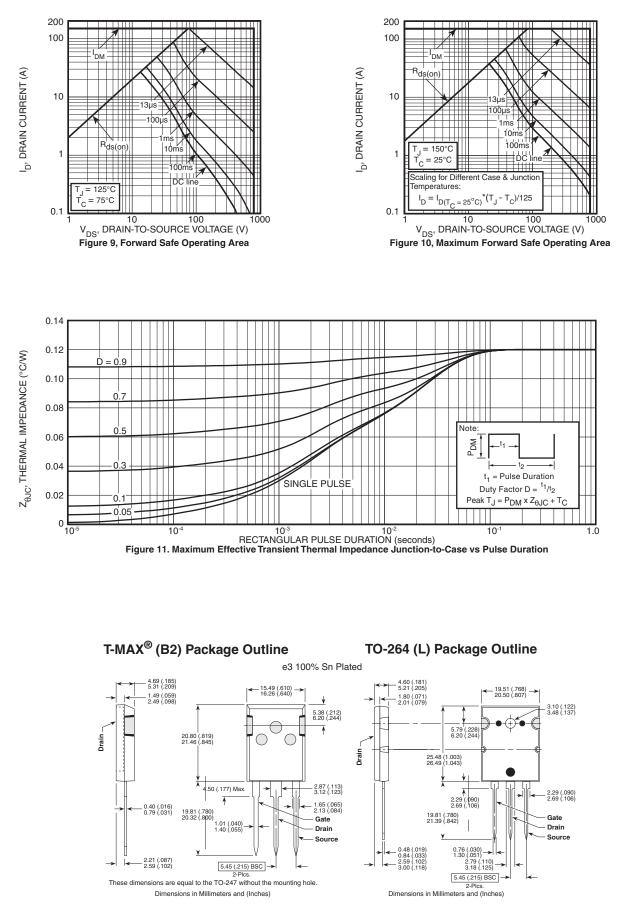
(4) C<sub>o(cr)</sub> is defined as a fixed capacitance with the same stored charge as C<sub>OSS</sub> with V<sub>DS</sub> = 67% of V<sub>(BR)DSS</sub>.
(5) C<sub>o(er)</sub> is defined as a fixed capacitance with the same stored energy as C<sub>OSS</sub> with V<sub>DS</sub> = 67% of V<sub>(BR)DSS</sub>. To calculate C<sub>o(er)</sub> for any value of V<sub>DS</sub> less than V<sub>(BR)DSS</sub>, use this equation: C<sub>o(er)</sub> = -2.17E-7/V<sub>DS</sub>^2 + 2.63E-8/V<sub>DS</sub> + 3.74E-11.

6 R<sub>G</sub> is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

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